

Table of Contents

- Series Editor Preface p. vii
- Introduction Antony John Kunnan and Nick Saville p. xi
- The Interviews p. 1
- 1 The Story Behind the Modern Language Aptitude Test Interview Charles W. Stansfield and Daniel J. Reed (in LAQ 1, 43-56); 2004 and John B. Carroll (1916-2003) p. 3
- 2 Biasing for the Best in Language Testing and Learning Interview Janna Fox (in LAQ 1, 235-251); 2004 and Merrill Swam p. 17
- 3 40 Years in Applied Linguistics Interview Antony John Kunnan (in LAQ 2, 35-50); 2005 and Alan Davies p. 35
- 4 At 80 Interview Nick Saville (in LAQ 2, 263-288); 2005 and John Trim (1924-2013) p. 51
- 5 People and Events in Language Testing: A Sort of Memoir Interview Nick Saville and Antony John Kunnan (in LAQ 3, 243-266); 2006 and Bernard Spolsky p. 76
- 6 The Founding Father of Language Testing in Japan Interview by Miyoko Kobayashi and Masashi Negishi (in LAQ 5, 244-266); 2008 Kenji Ohtomo p. 103
- 7 A Life in Language Testing Interview Daniel J. Reed and Melissa Bowles (in LAQ 5, 336-359); 2008 and Charles Stansfield p. 126
- 8 From Cloze to Consequences and Beyond Interview Anne Lazavaton (in LAQ 7, 255-219); 2010 and Elana Shohamy p. 150
- 9 The Founding Father of Language Testing in China Interview He Lianzhen and Qi Luxia (in LAQ 7, 359-311); 2010 and Gui Shichuan p. 184
- 10 Language Assessment: Its Development and Future Interview Jing Chen (in LAQ 8, 211-290); 2011 and Lyle F. Bachman p. 199
- 11 A Lifetime of Language Testing interview Tineke Brunfaut (in LAQ 11, 103-119); 2014 and J. Charles Alderson p. 238
- 12 The Accidental Language Tester Interview Jin Van (in LAQ 11, 338-351); 2014 and Liz Hamp-Lyons p. 238
- Index p. 255